

# **First Observation of an Electron Beam Emitted from a Diamond Amplified Cathode**

**Xiangyun Chang, Ilan Ben-Zvi, Andrew Burrill, Jorg  
Kewisch, Erik Muller, Triveni Rao, John Smedley, Erdong  
Wang, Yi-Chun Wang, Qiong Wu**

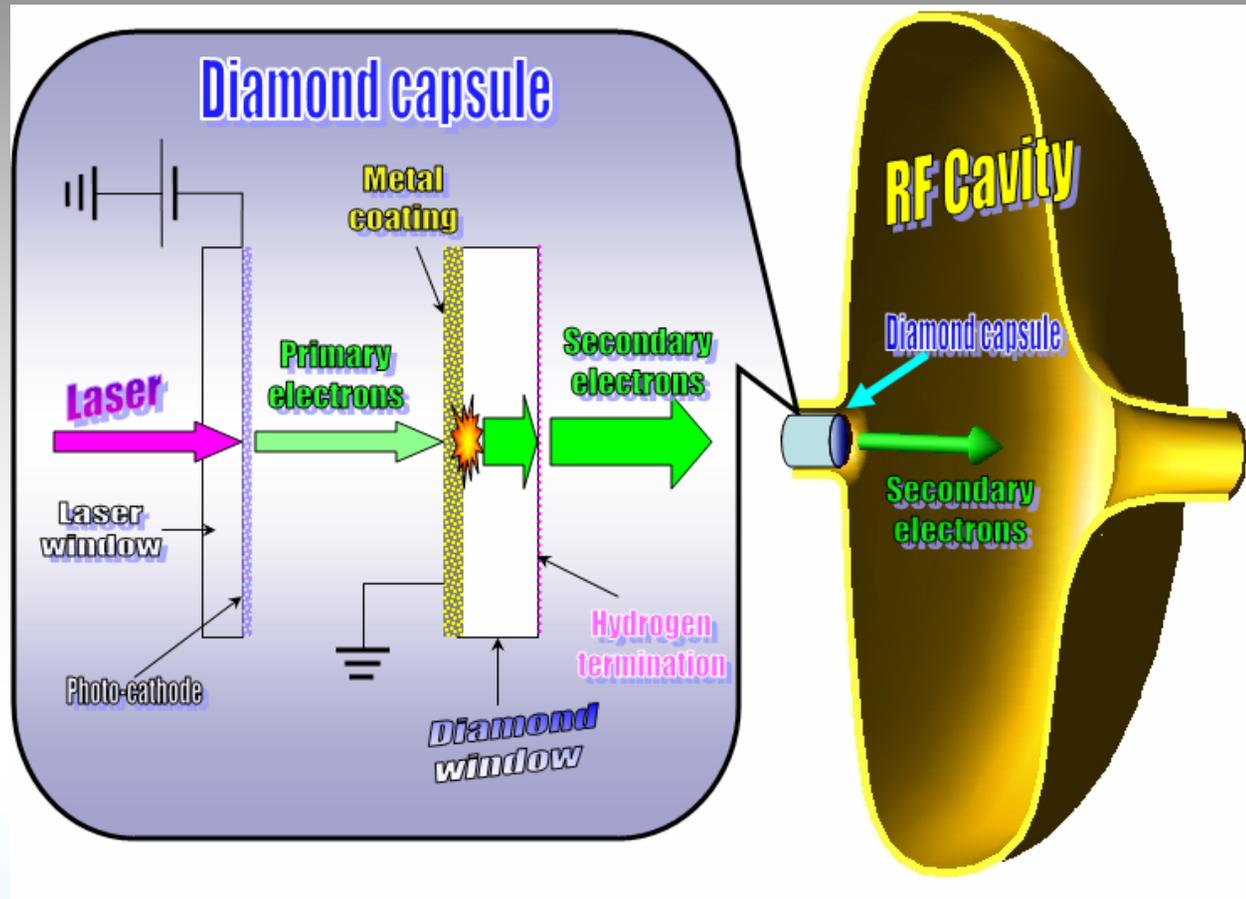


- For many years people can either have cathode with:
  - High QE, high bunch charge, high average current, low emittance but very short lifetime. Semiconductor cathodes
  - Or, long lifetime but low QE, low average current, high emittance. Metallic cathodes
- **For the first time we've demonstrated the cathode with:**
  - Effectively very high QE
  - Very high bunch charge
  - Very high average current
  - Low emittance
  - Extremely long lifetime.

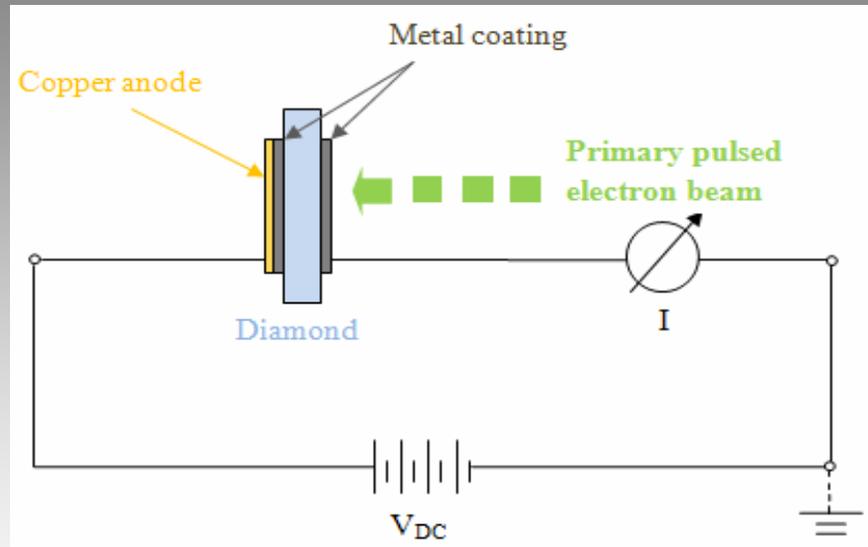


# The Diamond Amplified Photo-cathode (DAP) concept

- I. Primary electrons penetrate the metal coating and generate electron-hole pairs.
- II. Electron-hole pairs are separated by the RF electric field at the right phase.
- III. Secondary electrons drift through diamond.
- IV. Secondary electrons are emitted from the hydrogenated Negative Electron Affinity (NEA) surface.

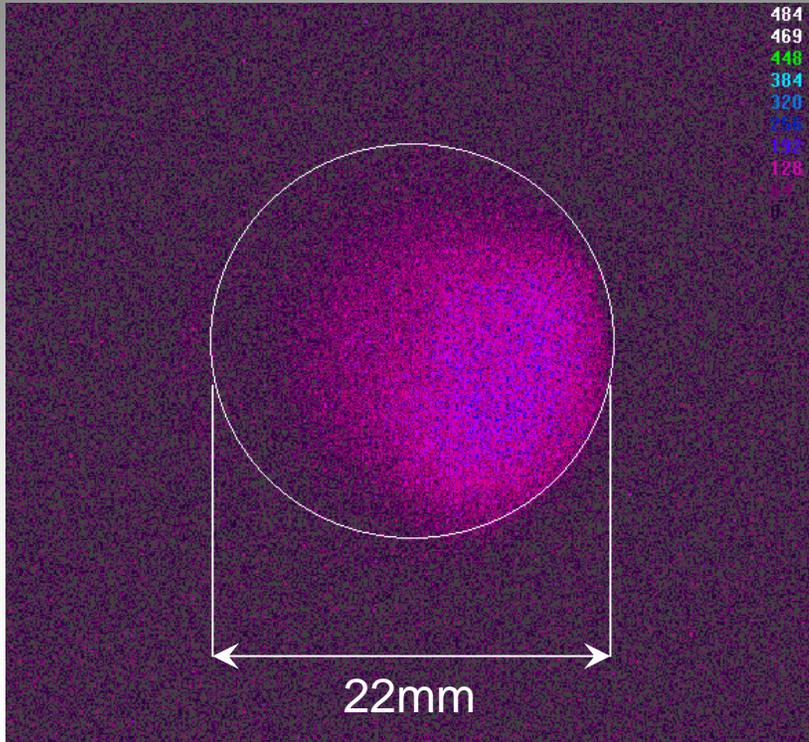


# *Transmission Mode Measurement*

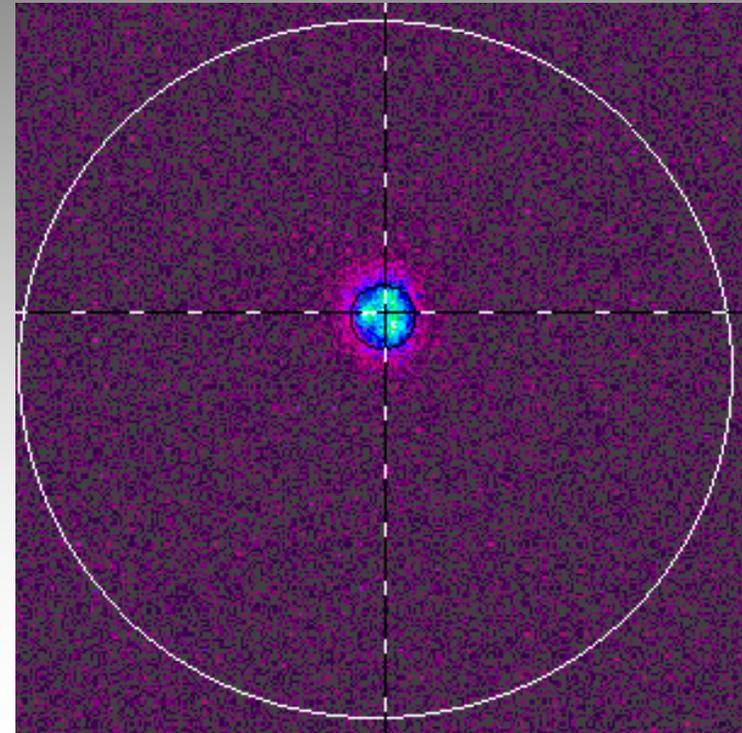


- I. Single-crystal, high-purity, synthetic diamonds greatly reduce electron and hole trapping in the diamond's bulk.**
- II. Gain vs. field does not vary with the primary electron density.**
- III. The saturation gain is independent of temperature.**
- IV. Diamonds are very robust.**
- V. Can handle very large current densities.**

# First observed beam from diamond amplified cathode



**Without focusing**

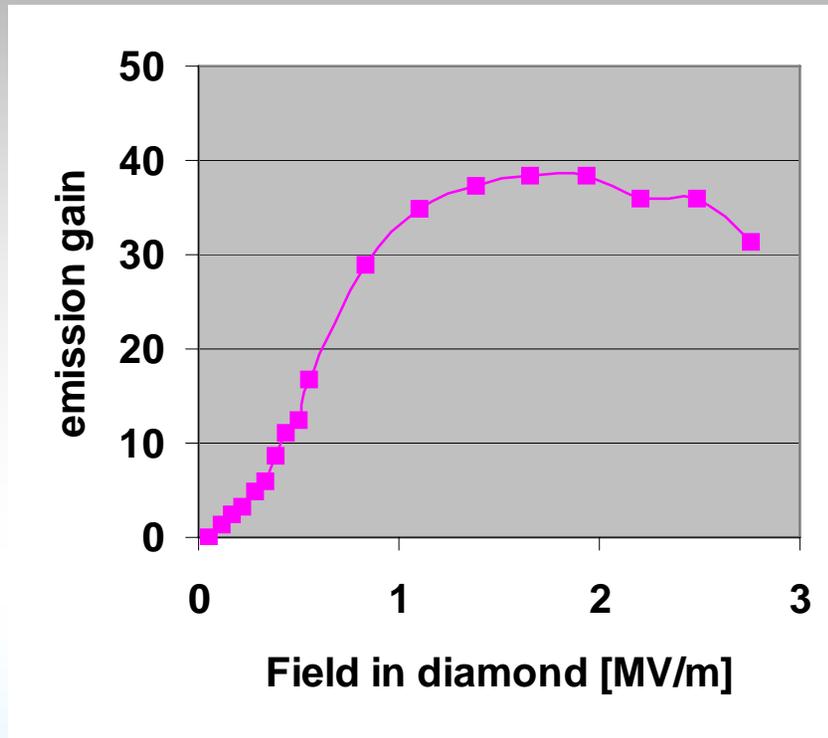


**With focusing and reduced  
primary current**

IPri=300nA. HV: 3kV (1.7MV/m in diamond).  
Freq. = 1kHz, Duty cycle = 0.001

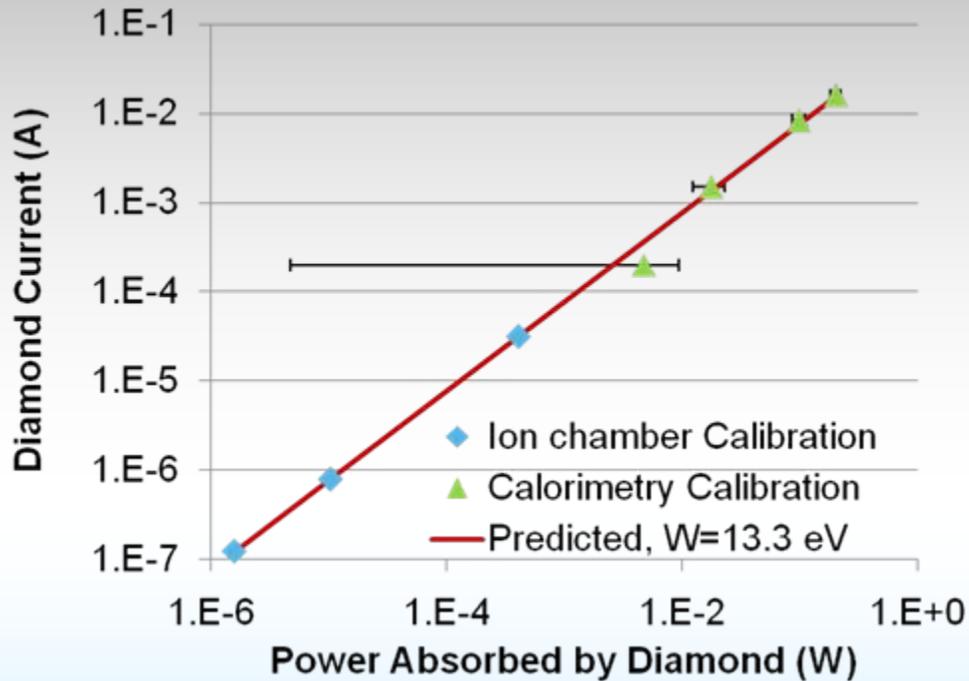
# Gain?

*Gain of 40 was measured in our current test conditions.*

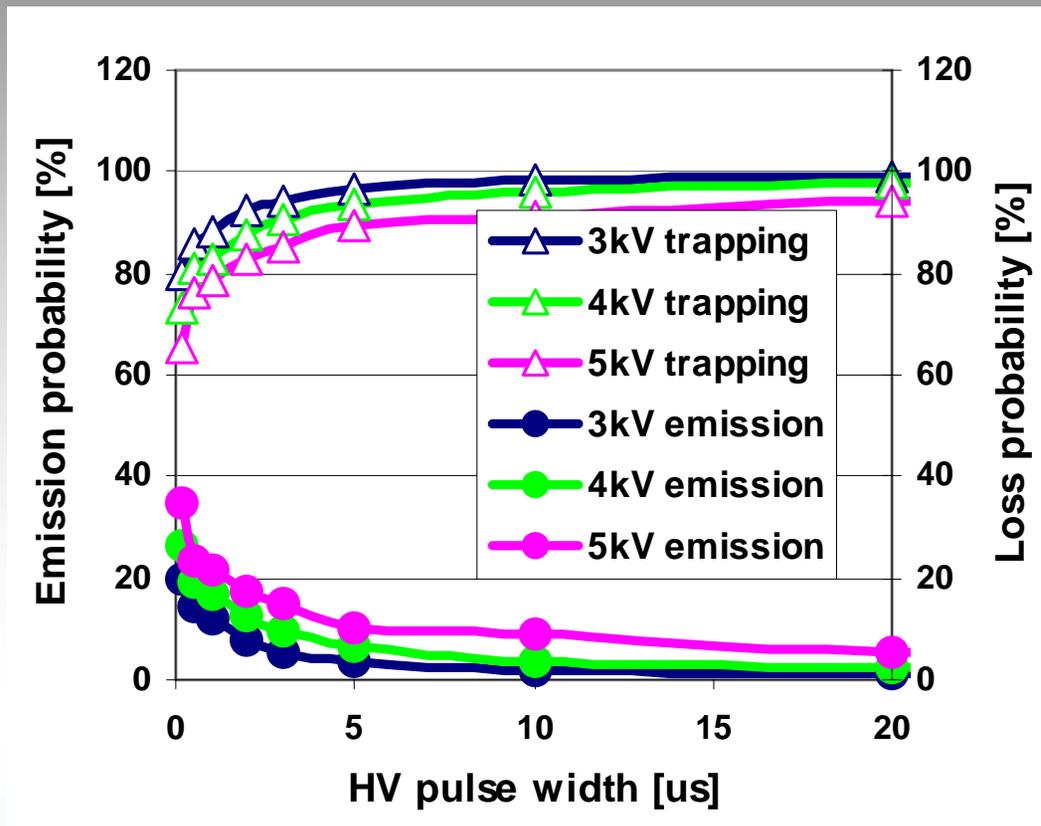


# Charge / bunch ?

- **>50pC/bunch/0.5mm<sup>2</sup>** (10nC/cm<sup>2</sup>) from the existing samples and conditions.
- Experiments using x-rays to generate current in diamond have demonstrated an average current of 40mA in a 2mm<sup>2</sup> area (**2A/cm<sup>2</sup>**)
- Current is linear with x-ray power from 100pW to 1W



# The emission probability on the hydrogenated surface?



**~40% @ 2.7MV/m, 200ns HV pulse width**

# Other characteristics of the diamond amplified cathode

- *Emission is independent of temperature. (From LN to 200C in our tests).*
- *Extremely robust*
  - ❑ *No observable emission degradation after days of exposure to the air.*
  - ❑ *About 50% degradation after exposure to the air for half year!*



# Summary

- **Phosphor screen image of the diamond amplified cathode emission is first time observed.**
- **At current experimental conditions we've measured:**
  - **Gain of 40**
  - **50pC/0.5mm<sup>2</sup>/bunch of bunch charge.**
  - **Emission probability of 40% on hydrogenated surface**
- **Extremely robust.**

## Promising methods R&D in progress

- **Emittance measurement (estimated to be ~0.1eV).**
- **Hydrogenation effects**
- **Other crystal orientations**
- **Room temperature RF gun test**
- **Other terminations**
- **SRF cavity test**

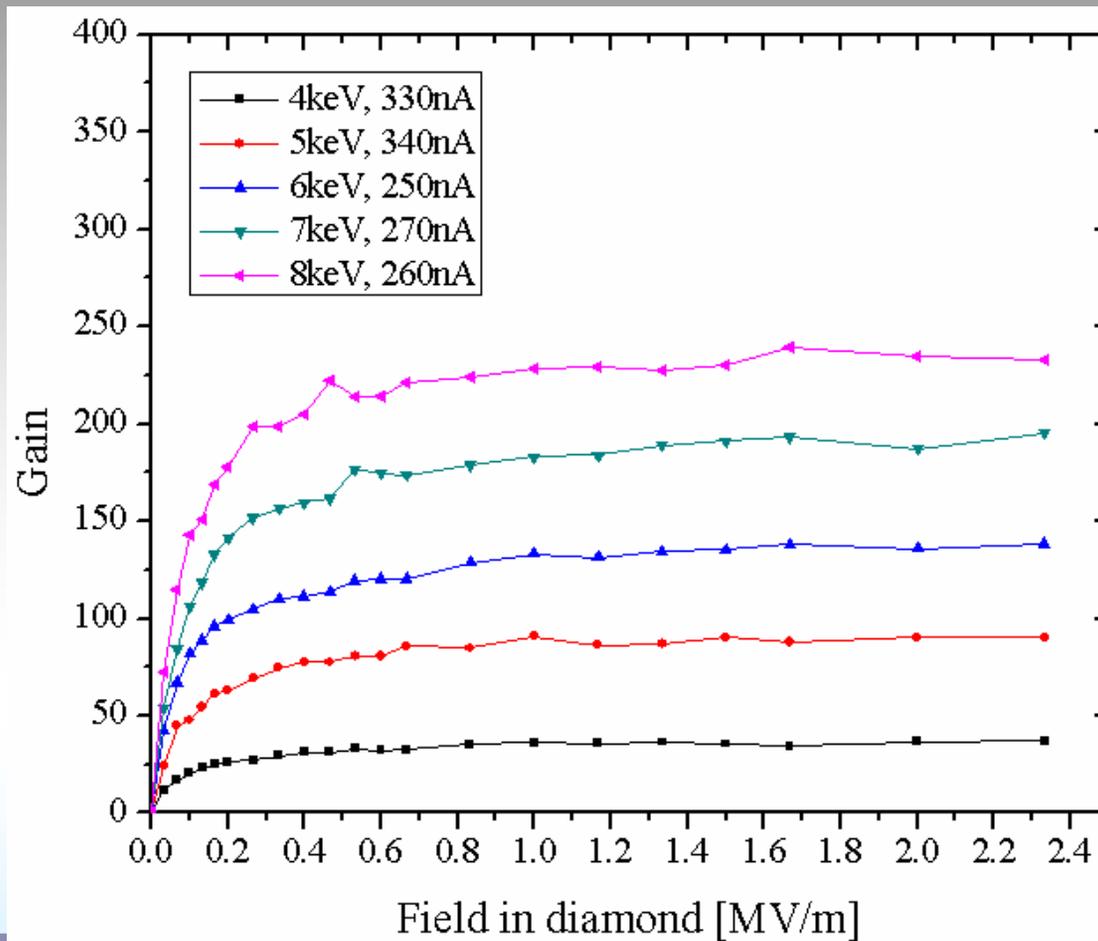
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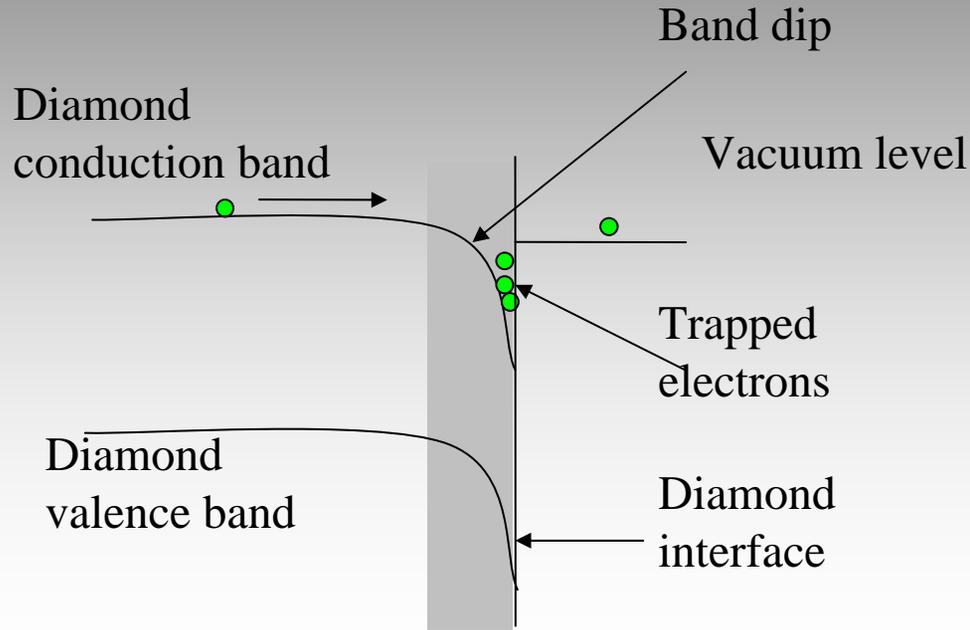
***Thank you!***



# Transmission gain



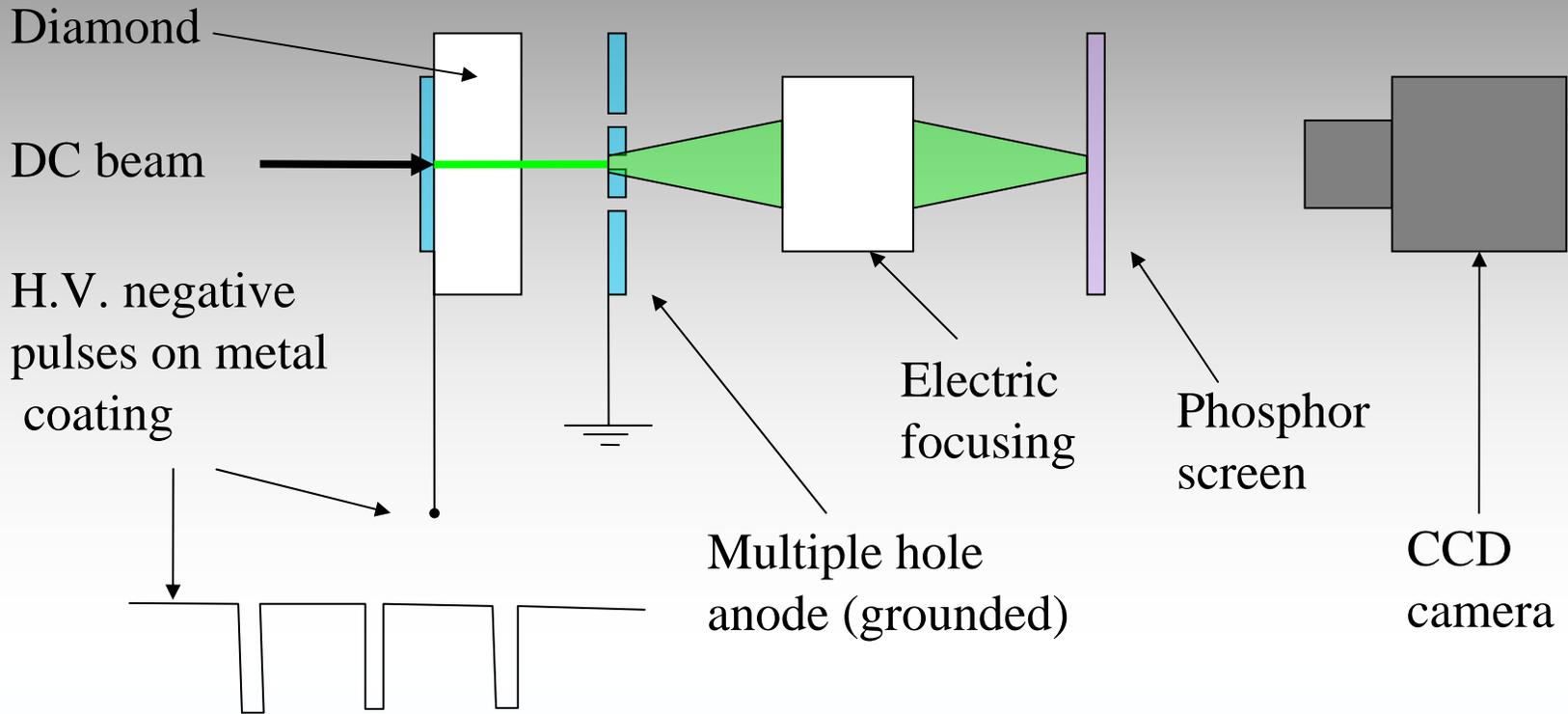
# Possible trapping mechanism



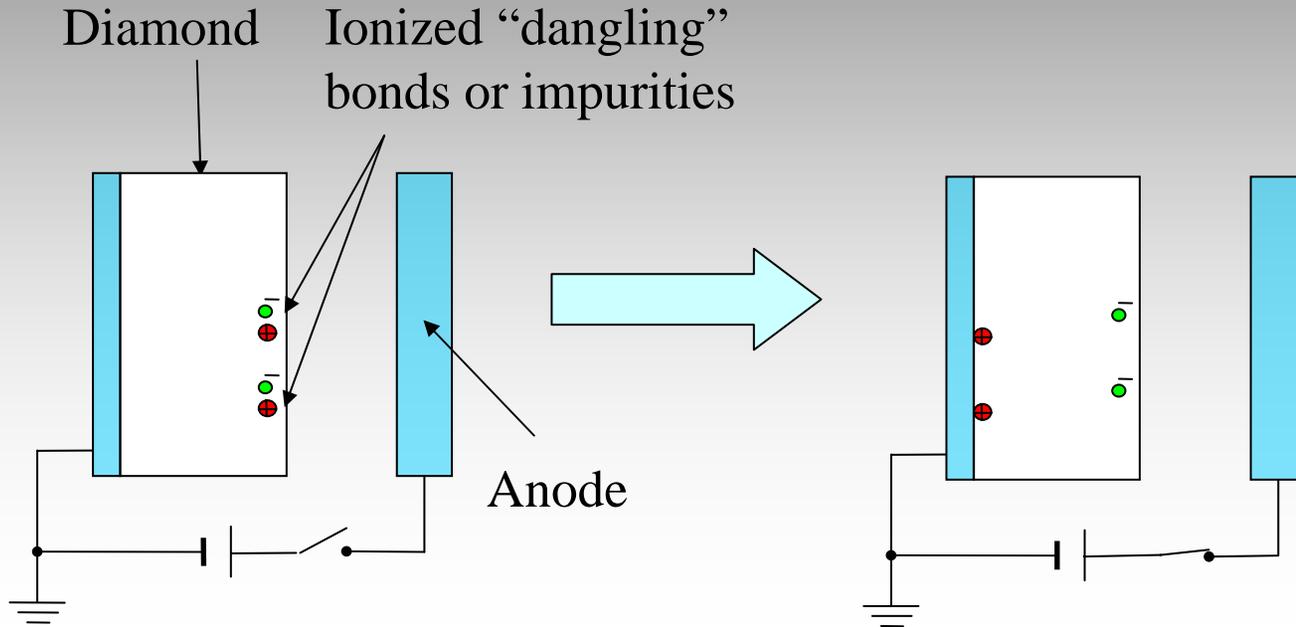
## Solutions:

- **Improving hydrogenation**
- **Choose [110] or [111] orientation diamonds**
- **Li, Na or other alkali elements terminations.**

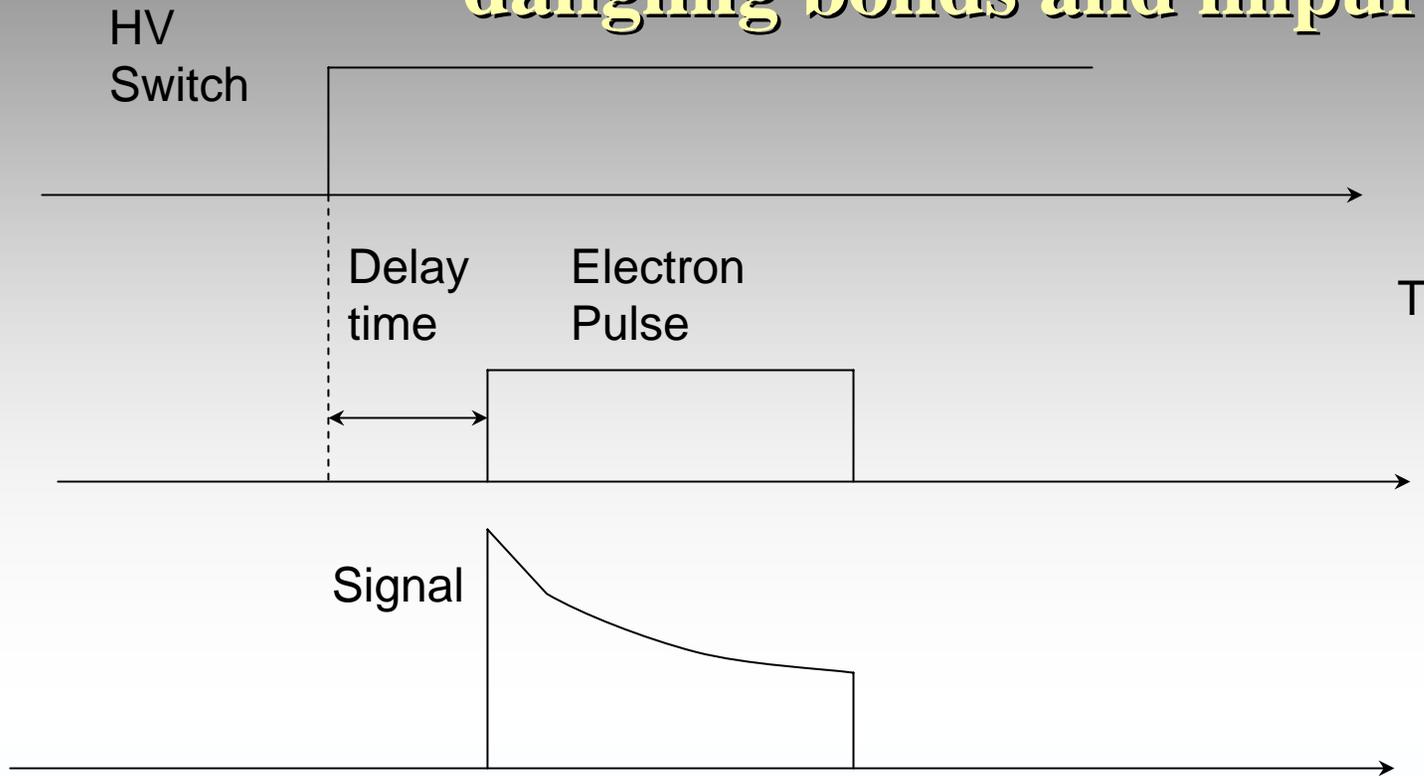
# Emission test diagram



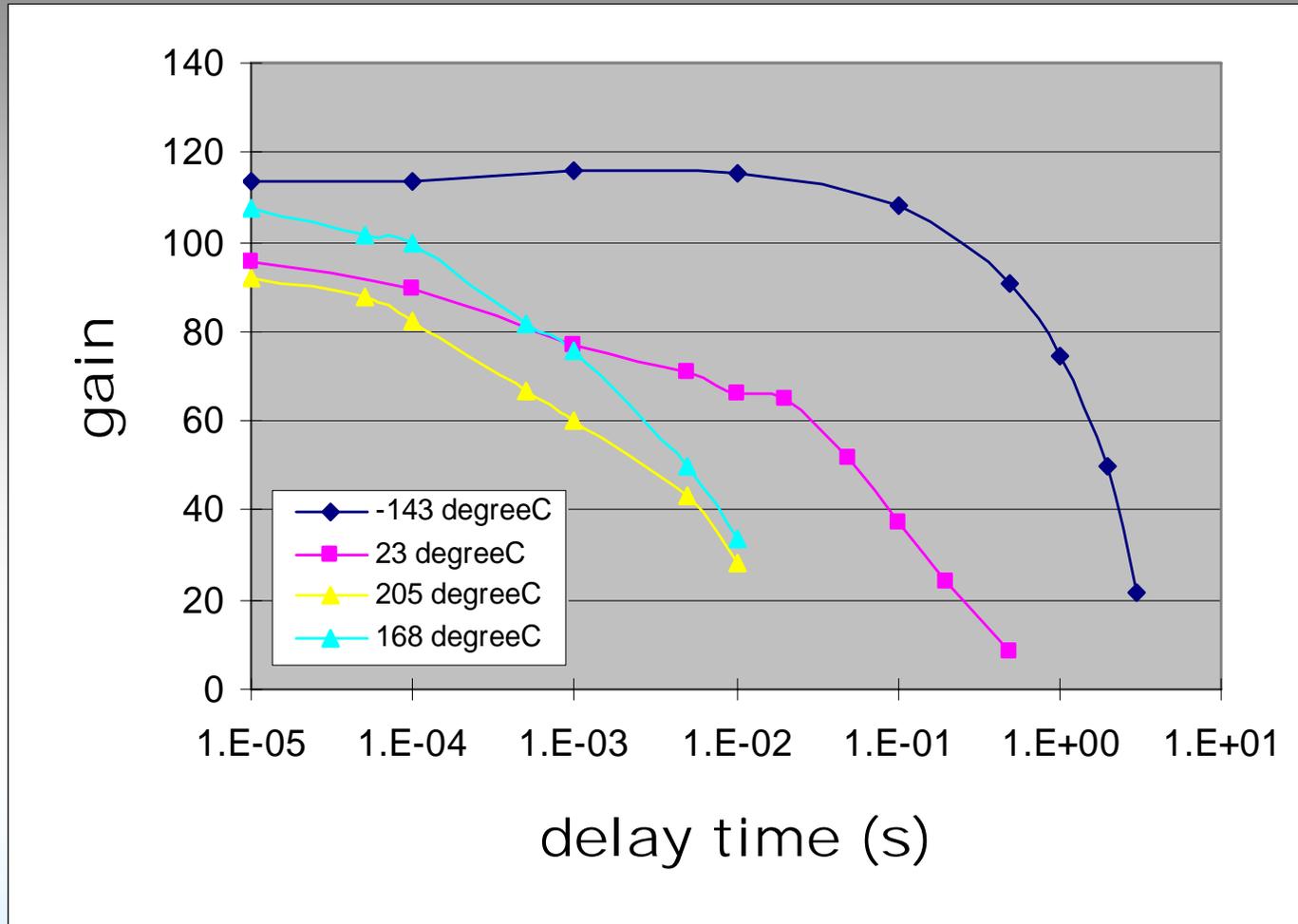
# Possible field shielding due to dangling bonds and impurities



# Test of field shielding due to dangling bonds and impurities

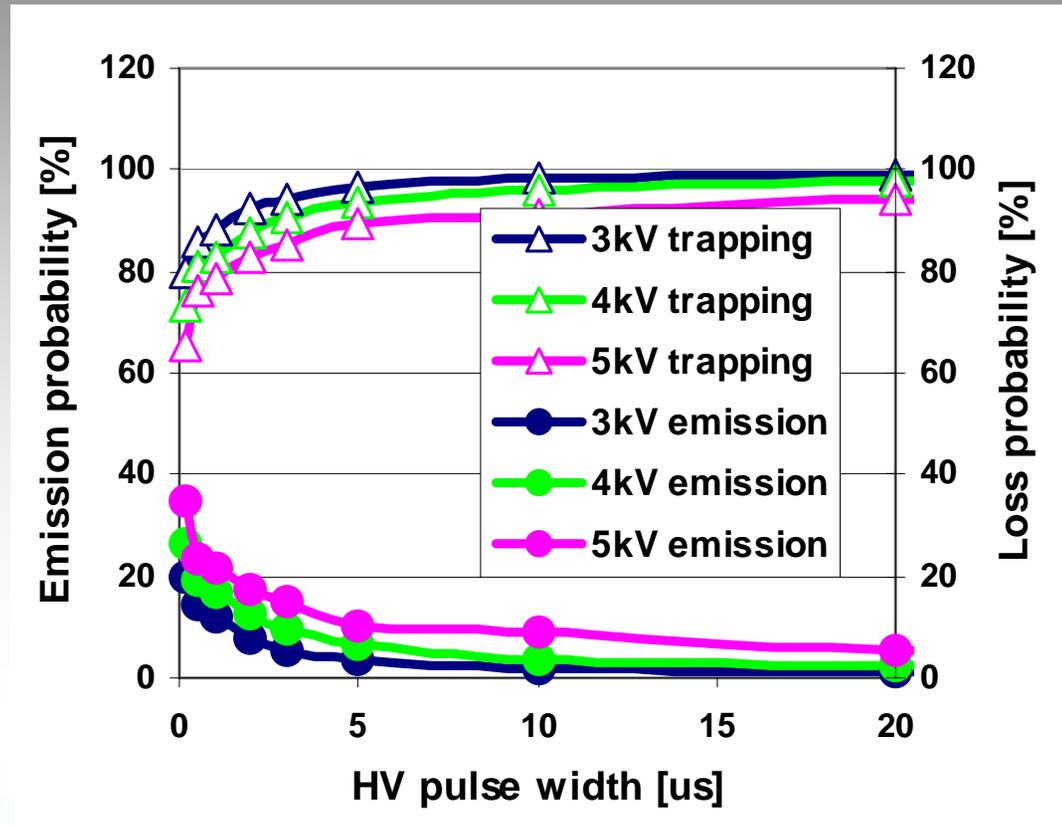


# High voltage is fixed at -500V

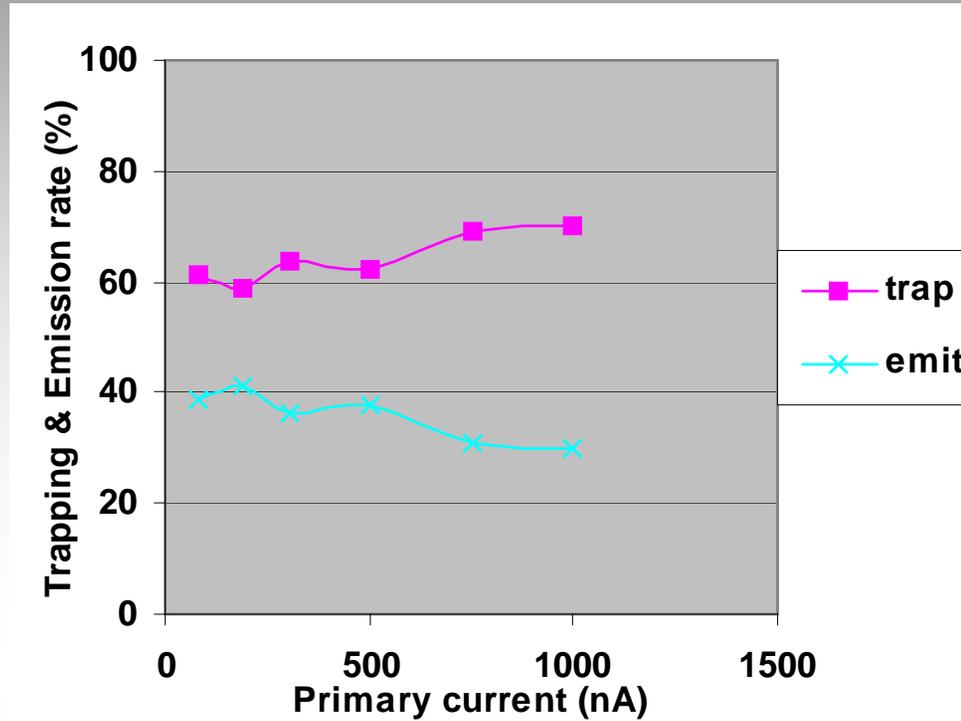


# The trapping probability near the H-surface?

- Control the emission pulse width and duty cycle accurately with the push-pull circuit
- Measure the integrated emission current. Calculate the emission gain.
- Compare to the data in the transmission mode to find the trapping probability.



# Trapping vs. primary current density



# Pulse response, 2 MV/m

- Pulse response to 1ns FWHM of x-rays ( $\sim 10\text{keV}$ ).  
Carrier transit time is consistent with expected velocity.

